Patrick Fiorenza received the M.Sc. in Physics and the PhD in Material Science from the University of Catania in 2003 and 2007, respectively. In 2005, he was visiting scientist at IMEC (Belgium). Since 2011 he is permanent staff Researcher at CNR-IMM. His research activity is mainly focused on carrier transport, trapping phenomena and reliability at Metal-Insulato-Semiconductor and Metal-Semiconductor interfaces in SiC and GaN. He has a recognized experience in characterization of advanced materials and devices by scanning probe microscopy. He is co-author of more than 100 papers and three book chapters.